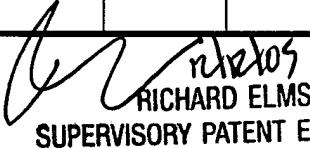


Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/796,270	WANG ET AL.
	Examiner	Art Unit
	Hien N. Nguyen	2824

ISSUE CLASSIFICATION							
ORIGINAL		CROSS REFERENCE(S)					
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
365	201	365	189.09 230.06				
INTERNATIONAL CLASSIFICATION							
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HIEN NGUYEN 12/09/05 (Assistant Examiner) (Date) <i>66 12/09/05</i> (Legal Instruments Examiner) (Date)		 RICHARD ELMS SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2800 (Primary Examiner) (Date)					
Total Claims Allowed: 21 <table border="1"> <tr> <td>O.G. Print Claim(s)</td> <td>O.G. Print Fig.</td> </tr> <tr> <td>1</td> <td>17</td> </tr> </table>				O.G. Print Claim(s)	O.G. Print Fig.	1	17
O.G. Print Claim(s)	O.G. Print Fig.						
1	17						

Claims renumbered in the same order as presented by applicant

Final	Original												
1		31		61		91		121		151		181	
2		32		62		92		122		152		182	
3		33		63		93		123		153		183	
4		34		64		94		124		154		184	
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6		36		66		96		126		156		186	
7		37		67		97		127		157		187	
8		38		68		98		128		158		188	
9		39		69		99		129		159		189	
10		40		70		100		130		160		190	
11		41		71		101		131		161		191	
12		42		72		102		132		162		192	
13		43		73		103		133		163		193	
14		44		74		104		134		164		194	
15		45		75		105		135		165		195	
16		46		76		106		136		166		196	
17		47		77		107		137		167		197	
18		48		78		108		138		168		198	
19		49		79		109		139		169		199	
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22		52		82		112		142		172		202	
23		53		83		113		143		173		203	
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25		55		85		115		145		175		205	
26		56		86		116		146		176		206	
27		57		87		117		147		177		207	
28		58		88		118		148		178		208	
29		59		89		119		149		179		209	
30		60		90		120		150		180		210	